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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/713,254	11/17/2003	Jong Jin Park	3811-0129P	4772
2292	7590 03/22/2005		EXAMINER	
BIRCH STEWART KOLASCH & BIRCH			LEE, SIN J	
PO BOX 747 FALLS CHURCH, VA 22040-0747		7	. ART UNIT	PAPER NUMBER
			1752	
			DATE MAILED: 03/22/2009	5 .

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)					
Office Anti-us Commence	10/713,254	PARK ET AL.					
Office Action Summary	Examiner	Art Unit					
The MAIL INC DATE of this committee is a	Sin J. Lee	1752					
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet	with the correspondence address					
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may within the statutory minimum of rill apply and will expire SIX (6) No cause the application to become	a reply be timely filed thirty (30) days will be considered timely. ONTHS from the mailing date of this communication ABANDONED (35 U.S.C. § 133).	n.				
Status							
1) Responsive to communication(s) filed on 17 No	ovember 2003.						
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is							
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.							
Disposition of Claims							
 4) Claim(s) 1-11 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw 5) Claim(s) is/are allowed. 6) Claim(s) 1-9 and 11 is/are rejected. 7) Claim(s) 10 is/are objected to. 8) Claim(s) are subject to restriction and/or 							
Application Papers							
9) The specification is objected to by the Examiner 10) The drawing(s) filed on is/are: a) access applicant may not request that any objection to the objected to by the Examiner Replacement drawing sheet(s) including the correction access access and the correction access access and the correction access acces	epted or b) objected drawing(s) be held in abey on is required if the drawi	rance. See 37 CFR 1.85(a). ng(s) is objected to. See 37 CFR 1.121(d).				
Priority under 35 U.S.C. § 119							
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the prior application from the International Bureau * See the attached detailed Office action for a list of	s have been received. s have been received in ity documents have be (PCT Rule 17.2(a)).	Application No en received in this National Stage					
Attachment(s)							
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date 11-17-2003. 	Paper N	v Summary (PTO-413) o(s)/Mail Date If Informal Patent Application (PTO-152)					

Application/Control Number: 10/713,254

Art Unit: 1752

DETAILED ACTION

Claim Rejections - 35 USC § 103

1. Claims 1-9 and 11 are rejected under 35 U.S.C. 103(a) as being unpatentable over Aoki (5,561,026) in view of Anazawa et al (US 2001/0050219 A1) and Irving et al (4,439,291).

Aoki teaches a photosensitive resist material (*useful for the production of semiconductors*) comprising fullerenes that contain photosensitive groups, which are obtained by adding photosensitive groups (such as methacryloyl group) to the fullerene (see col.1, lines 7-15, col.2, lines 39-54). Specifically, in Example 1, Aoki teaches a reaction product of a (n-propylamine modified) fullerene and *methacryloyl chloride* (which teaches present Formula 1 of claim 2), and the resultant product contains the following moiety

Aoki forms a film of photosensitive resist material (that contains the modified fullerene as discussed above) onto a silicon wafer by spin-coating his photosensitive resist solution and then pre-heating the coating (see col.2, lines 45-49 and Example 1). The resist film is then exposed to a light source such as UV light, deep UV light, X-ray, or electron beam and then subjected to development to obtain a resist pattern. Therefore, the prior art teaches present method of claim 1 except for using carbon nanotubes in present step (a) and using photoinitiator together with the nanotubes in present step (b).

Application/Control Number: 10/713,254

Art Unit: 1752

Anazawa teaches that carbon nanotube is made up of carbon atoms only in the same manner as the fullerene and is discovered to possess the photosensitive effect and a function as a semiconductor and the like (see [0006]). Anazawa furthermore states that the fullerene also has a property as a semiconductor and it also exhibits a photosensitive effect (see [0005]). Based on this teaching, it would have been obvious to one of ordinary skill in the art to use carbon nanotube in Aoki's Example 1 (instead of the fullerene) and modify the carbon nanotube with methacryloyl chloride because fullerene and carbon nanotubes were art-recognized equivalents at the time the invention was made. Therefore, Aoki in view of Anazawa would render obvious present step (a) of claim 1.

Also, although Aoki does not explicitly state that it is using a photoinitiator along with the fullerene, it is well known in the art to use photoinitiators (such as *benzoin*, acetophenones, or *benzophenones*) in an *(meth)acryloyl group*-containing photosensitive composition in order to shorten the exposure time required for photopolymerization as evidenced by Irving et al (see abstract, col.9, lines 12-15, col.17, lines 19-33). Therefore, it would have been obvious to one of ordinary skill in the art to use photoinitiators in Aoki's photosensitive resin composition in order to shorten the exposure time as taught by Irving. Therefore, Aoki in view of Irving would render obvious present step (b) of claim 1.

Thus, Aoki in view of Anazawa and Irving would render obvious present inventions of claims 1, 2, and 4-9 (present claim languages of claims 5 and 6 do not require the presence of a special grade photoinitiator or a co-polymerizable

Art Unit: 1752

photoinitiator; they only require that *if* the photoinitiator of present claim 4 happens to be a special grade photoinitiator or a co-polymerizable photoinitiator, then those photoinitiators have to be selected from those listed in claims 5 and 6 respectively).

With respect to present claim 3, Anazawa teaches ([0020]) a method of manufacturing carbon nanotubes by reducing the pressure inside a system to 1.3 Pa or lower; supplying a carboniferous liquid state material to raise the pressure inside the system to at least 1.3 kPa to 93.3 kPa; generating *arc discharges*; supplying the carboniferous liquid state material in discharge plasma created by the arc discharges; and disintegrating or exciting the carboniferous liquid state material to produce the carbon nanotubes. Therefore, Aoki in view of Anazawa and Irving would render obvious present invention of claim 3.

With respect to present claim 11, Aoki teaches that such resins as polystyrene or phenolic resins can be used in combination with his photosensitive materials of his invention (see col.3, lines 40-45). Therefore, Aoki in view of Anazawa and Irving would render obvious present invention of claim 11.

Allowable Subject Matter

2. Claim 10 is objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims. Aoki does not teach or suggest the use of additional monomers or oligomers containing double bonds as presently required in claim 10.

Art Unit: 1752

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sin J. Lee whose telephone number is 571-272-1333. The examiner can normally be reached on Monday-Friday from 9:00 am EST to 5:30 pm EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Cynthia Kelly, can be reached on 571-272-1526. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

8. A. L

S. Lee

March 20, 2005

Patent Examiner

Technology Center